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Session I: On-wafer Measurements

Differential Broadband Single-Sweep 70 kHz-220 GHz Wafer-Level System: First Calibration and Measurement Characteristics.....1

Andrej Rumiantsev¹, Jon Martens², Steve Reyes²
¹MPI Corporation, ²Anritsu Company

Reduced Calibration Error Employing Parametrized EM models and DC Load Extraction.....5

Ehsan Shokrolahzade¹, Carmine De Martino², Marco Spirito¹
¹Delft University of Technology, ²Vertigo Technologies B.V.

Traceable Lumped-Element Calibrations up to 110 GHz on Commercial Calibration Substrates.....9

Uwe Arz¹, Gia Ngoc Phung¹, Andrej Rumiantsev²
¹Physikalisch-Technische Bundesanstalt, ² MPI Corporation

Session II: Nonlinear Measurements

The Dynamic Gain Model.....13

Jan Verspecht, Sam Kusano, Augustine Stav
Keysight Technologies, Inc.

Linking Nonlinear Distortion and a Signal's Cumulative Distribution Function: A Measurement Based Approach.....17

S. De Keersmaecker¹, Y. Rolain¹, D. Peumans¹, P. Barmuta², G. Vandersteen¹
¹Vrije Universiteit Brussel, ²National Instruments corp.

Experimental Validation of ASM-HEMT Nonlinear Embedding Modeling of GaN HEMTs at X-band.....21

Miles Lindquist¹, Patrick Roblin¹, Nicholas C. Miller², Devin Davis³, Ryan Gilbert³, Michael Elliott³
¹Ohio State University, ²Air Force Research Lab, ³KBR

A Comprehensive Large-Signal RF Test System for Advanced Acoustic Device Performance and Reliability Characterization.....25

Divya Gamini, John Fendrich, Arthur Durham, Denny Limanto, Chris Money
Qorvo

Session III: Noise and Linear Measurements

Noise Measurements in the Presence of Large Signal Transients and Studies of Recovery Effects.....29

Jon Martens
Anritsu Company

Frequency Converting Noise Receiver Calibration for Mixer Noise Parameter Extraction.....34

Jonas Urbonas, Gary Simpson
Maury Microwave Corp.

Empirical Study on the Validity of the Modal Separation Approach for Deembedding of Highly Asymmetrical Passive Differential Devices.....37

Milan Rother¹, Martin Maier¹, Maciej Wojnowski², Vadim Issakov^{1,2}

¹Technische Universität Braunschweig, ²Infineon Technologies AG

Study on Measurement Discontinuity during On-wafer TRL Calibration of 28FD-SOI Devices up to 110GHz.....41

Karthi Pradeep^{1,2}, Sebastien Fregonese¹, Marina Deng¹, Benjamin Dormieu², Patrick Scheer², Thomas Zimmer¹

¹IMS laboratory, University of Bordeaux, ²STMicroelectronics

Extraordinary Permittivity Characterization Using 4H-SiC Substrate-Integrated-Waveguide Resonators.....46

Lei Li¹, Steve Reyes², Mohammad Javad Asadi¹, Xiaopeng Wang¹, Gianluca Fabi¹, Erdem Ozdemir¹, Weifeng Wu³, Patrick Fay³, James C. M. Hwang¹

¹Cornell University, ²Anritsu Company, ³University of Notre Dame

Session V: Modulated-Signal Measurements

VNA-Based Testbed for Accurate Linearizability Testing of RF Beamforming Arrays Under Modulated Signal.....50

Nizar Messaoudi^{1,2}, Ahmed Ben Ayed¹, Joel Dunsmore², Slim Boumaiza¹

¹University of Waterloo, ²Keysight Technologies

Improvements in 6G (D-band) Amplifier EVM Measurements using Clock-Locked Sources.....54

Joel Dunsmore, Jean-Pierre Teyssier

Keysight Technologies

Iterative Calibration Method for Integrated Tunable mmW Vector-Sum Phase Shifter.....58

Markku Jokinen¹, Alok Sethi¹, Olli Kursu¹, Timo Rahkonen², Marko E. Leinonen¹, Aarno Parssinen²

¹Centre for Wireless Communications, University of Oulu, ²Electronics Circuits and Systems Research Unit, University of Oulu

Recommended Practices for Calibrated Millimeter-Wave Modulated-Signal Measurements.....62

Paritosh Manurkar^{1,2}, Joshua M. Kast^{2,3}, Dylan F. Williams², Robert D. Horansky², Daniel G. Kuester², Kate A. Remley²

¹University of Colorado, ²National Institute of Standards and Technology, ³Colorado School of Mines

Session VI: OTA Measurements

A Deep Reinforcement Learning Approach for Automated Chamber Configuration Replicating mmWave Directional Industrial Channel Behavior.....66

Mohamed Kashef (Hany), Sudantha Perera, Carnot Nogueira, Richard Candell, Kate A. Remley, Matthew T. Simons

Communications Technology Laboratory, National Institute of Standards and Technology

Calibration approaches in Multi-Node Antenna Characterization Setups.....72

R.A. Coesoij, F.A. Musters, D. Roos, T. van Velden, M. Spirito

Delft University of Technology

OTA Measurement Technique for Sub-THz Integrated Lens Antennas.....76

Kimmo Rasilainen¹, Marko E. Leinonen¹, Mostafa Jafari Nokandi², Jiangcheng Chen¹, Klaus Nevala¹, Timo Rahkonen², and Aarno Parssinen¹

¹Centre for Wireless Communications, University of Oulu, ²Circuits and Systems Research Unit, University of Oulu

Challenges in Measurement of Broadband THz Photoconductive Antennas.....80

Zach Uttley¹, Jose Santos Batista¹, Mahmudul Doha³, Katie Welch², Hugh Churchill^{2,3}, Magda El-Shenawee¹

¹Department of Electrical Engineering, University of Arkansas, ²Material Science and Engineering Program, University of Arkansas, ³Physics Department, University of Arkansas

Interactive Forum

Pulsed Time Domain Reflectometry for Microwaves and Acoustics.....N/A

Charles Jackson

RFMS Department, Northrop Grumman

Tunable Distributed Feedback Laser Based Frequency Hopping in Terahertz Communications.....84

Kathirvel Nallappan, Maksim Skorobogatiy

Polytechnique Montreal

Demonstration of TRL Calibration Performance on mmW PCBs using WSMP Connectors.....88

Yagmur Ozturk, Niru K. Nahar, Kubilay Sertel

The Ohio State University